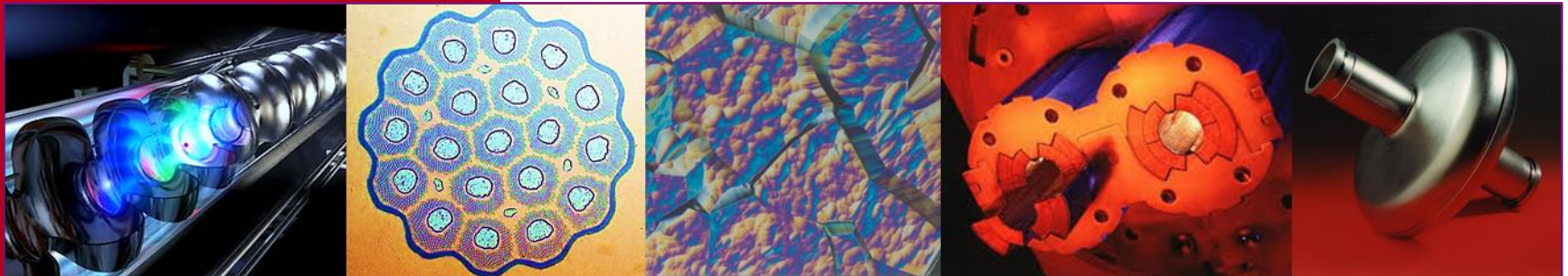


DE LA RECHERCHE À L'INDUSTRIE



SUPERCONDUCTIVITY IN ACCELERATORS PART II : MIXED STATE



université
PARIS-SACLAY

www.cea.fr

JUAS 2025 | Claire ANTOINE

MAGNETS VS RF CAVITIES





Magnets \neq RF Cavities !!!! !!!!

■ Magnet (DC) :

- One aims at very high current densities with 0 resistance
- It means:
 - Mixed state
 - Non moving, trapped vortices (medium fields: $H < H_{irr}$)
 - Defects are voluntarily introduced to \uparrow pinning and $\uparrow \lambda$ ($\downarrow \downarrow H_{C1}$ et $\uparrow \uparrow H_{C2}$)
 - $J < J_C \lll J_D$



■ Cavities

- One aims at very high field with minimal dissipation (but $\neq 0$ 😞)
 - H variable, $H_{max} \sim H_{SH}$ ($= f(H_C)$)
 - Vortices cannot keep pinned at this frequency \Rightarrow very high dissipations (!),
 - One has to prevent V_x entering: keep in **Meissner state** !
 - Reduce # of defects (promoting early V_x penetration), $\Rightarrow \uparrow \uparrow$ effective H_{C1}



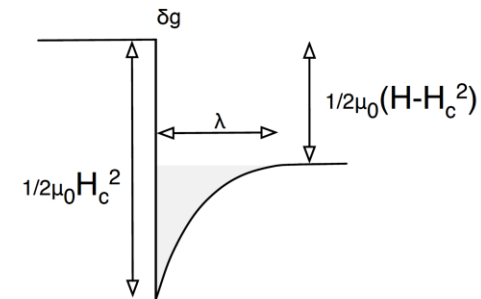
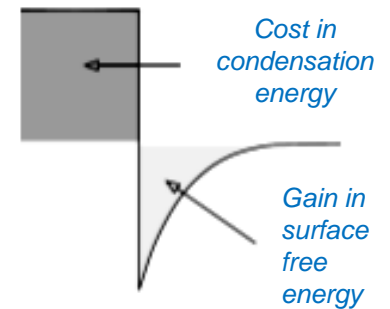
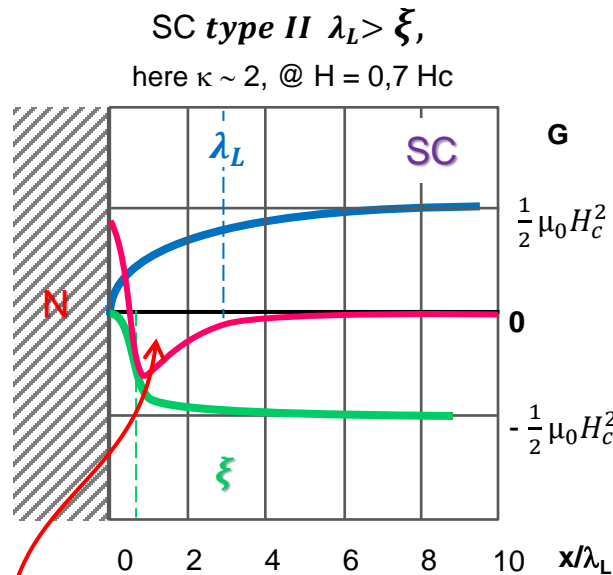
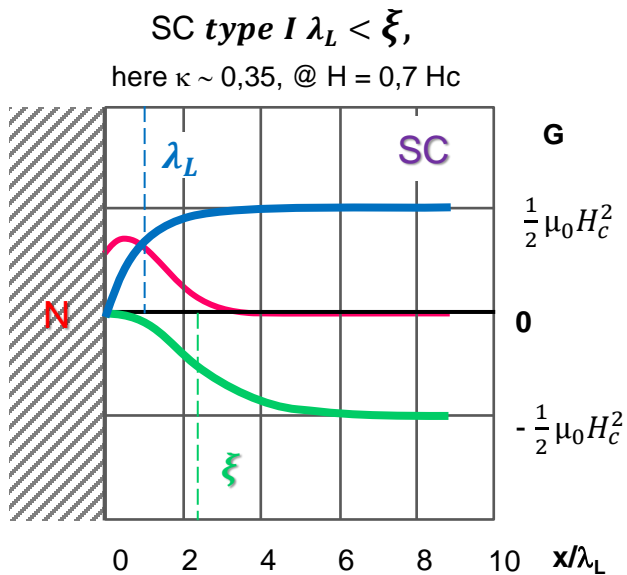
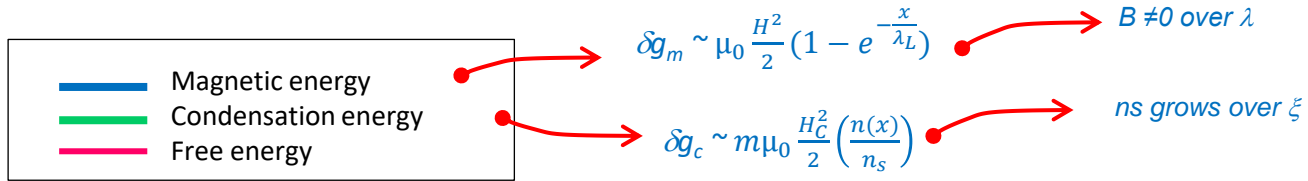
■ **Good SC for magnet applications are bad for cavities!**

■ **And vice versa !**

*For the recall:
1 \Rightarrow vortex, many \Rightarrow "vortices"*

VORTICES (I): PENETRATION INSIDE THE SUPERCONDUCTOR

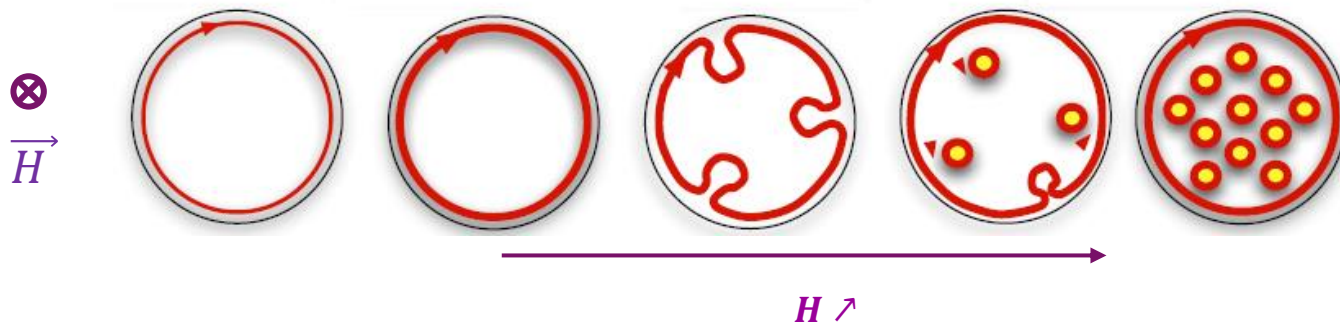




Free energy < 0

- Creation of a normal/SC interface is energetically favorable in type II SC
- At equilibrium (transition) $|g_n| = |g_s|$ except close to the surface





Thin sample, \perp field

Minimization of free energy:

- Normal zones as small as possible ($\varnothing \sim 2\xi$); → *This holds only for $\xi < \lambda$
=> Type II SC*
- Magnetic size $\varnothing \sim 2\lambda$ ($V_x = \text{normal zone w. 1 flux line + screening current}$).
- Number of V_x is the one that minimize $\Delta G/L$ (*depends on applied H*) and sample dimension
- Vortices repel each other (*but attract antivortices*)
- Surface stabilizes the apparition of the SC mixed state
 - Nucleation always occurs at surface, V_x always emerge \perp to the surface
 - In \perp field : boundary conditions are unchanged
 - In \parallel field : $E_{nucleation}^{Surf} < E_{nucleation}^{Bulk}$ → surface superconductivity can be observed in specific geometries (B_{C3}) (*on a thickness $\ll \lambda_L$*).²



Surface barrier

(Bean & Livingston, 1964)

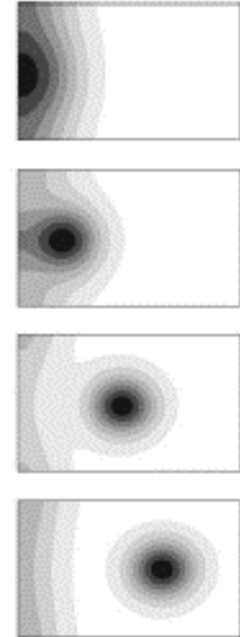
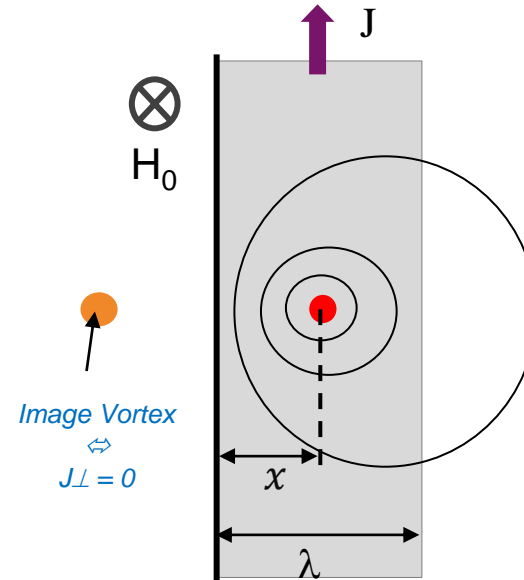
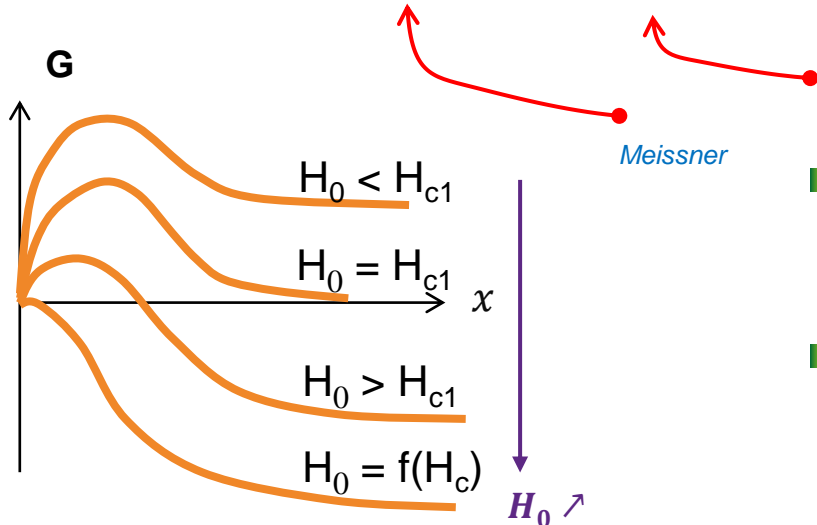
- Boundary conditions ($J_{\perp} = 0$) \equiv "image" vortices

- Supercurrent tends to push V_x inside
- Image antivortex tends to pull it out

- Before entering the material V_x have to cross a surface barrier:

- V_x thermodynamic potential :

$$G(x) = \phi_0 \left[H_0 e^{-x/\lambda} - H_v(2x) + H_{c1} - H_0 \right]$$



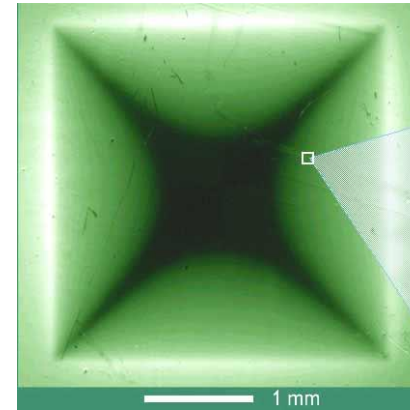
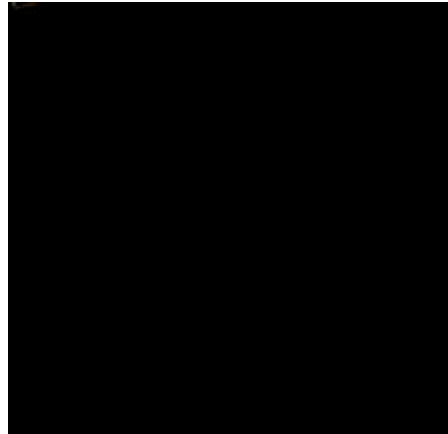
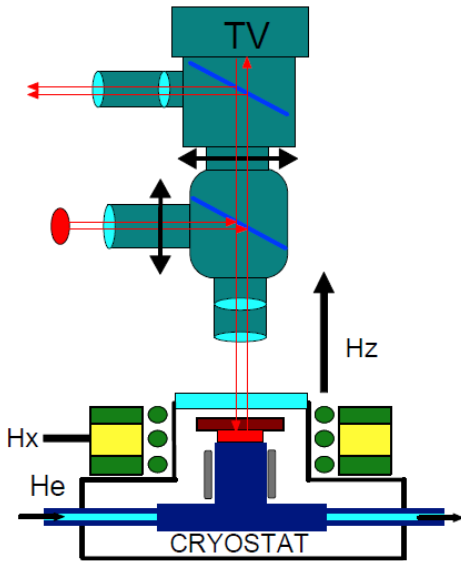
- "Ideal surface"

- Barrier disappears only at $H_{SH} \sim f(H_c) > H_{c1}$
- Rationale used to predict SRF limits

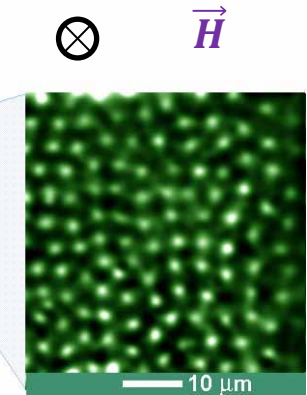
- BUT

- If \exists localized defect w.: $H_c^{Local} \ll H_c^{bulk}$ (or $T_c^{Local} \ll T_c^{bulk}$) \Rightarrow early penetration of 1 or several V_x there

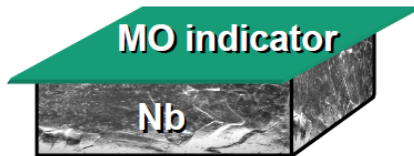
- In \perp field : demagnetization effect , local field depends on the shape



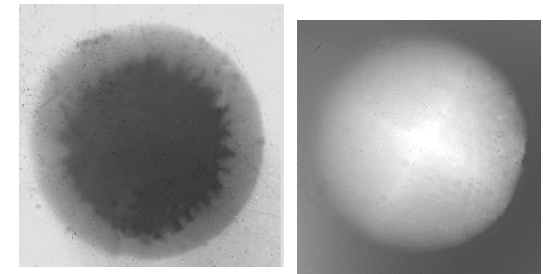
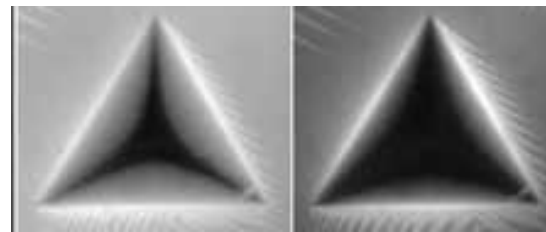
Nb_2Se



(Abrikosov V_x lattice)



Dark contrast : $B \Rightarrow 0$
Light contrast : $B \nearrow$

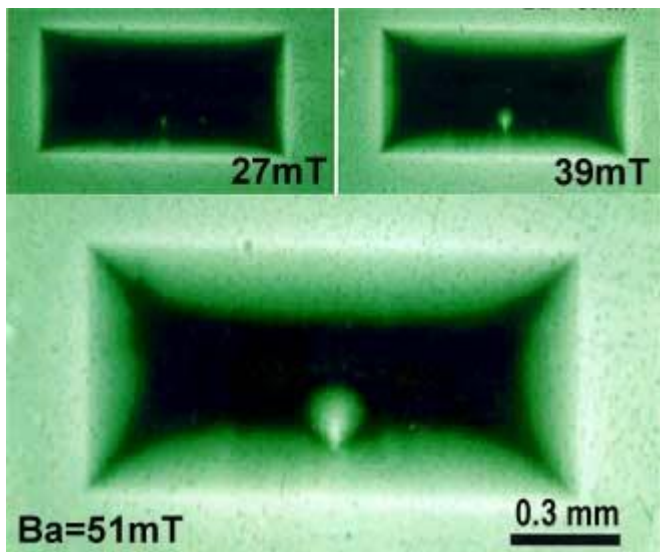


<http://www.mn.uio.no/fysikk/english/research/groups/amks/superconductivity/mo/>



■ Localized defect effect...

YBa₂Cu₃O₇ film w. one single defect ↓



<http://www.mn.uio.no/fysikk/english/research/groups/amks/superconductivity/mo/>

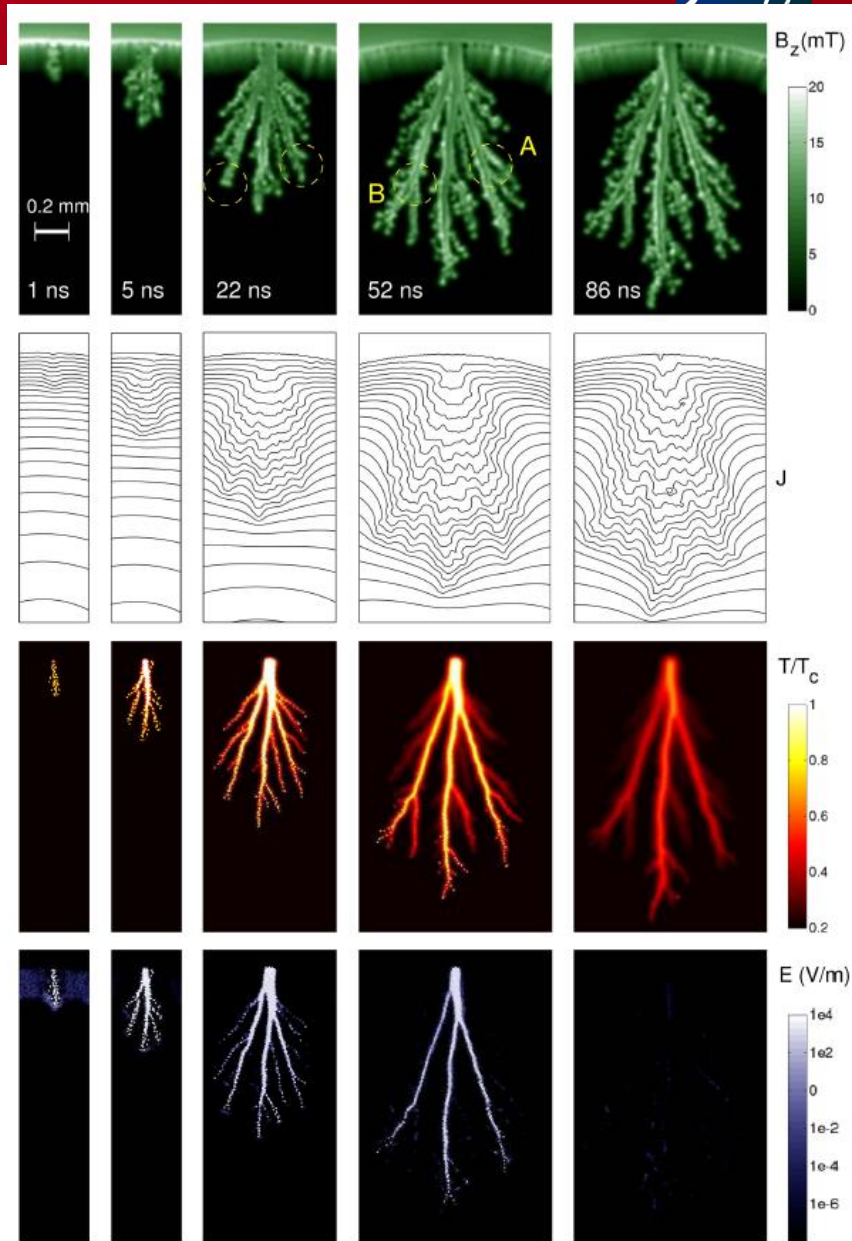
■ Vx penetration (~100 μm) during 1! RF period (ns)



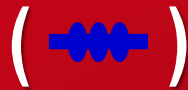
■ “flux jumps” ≡ avalanche penetration, observed in transient state (so also expected in RF)

MgB₂ →

http://www.nature.com/srep/2012/121126/srep00886/full/srep00886.html?message-global=remove&WT.ec_id=SREP-20121127



VORTEX IN PRESENCE OF ELECTRIC FIELD AND/OR CURRENT

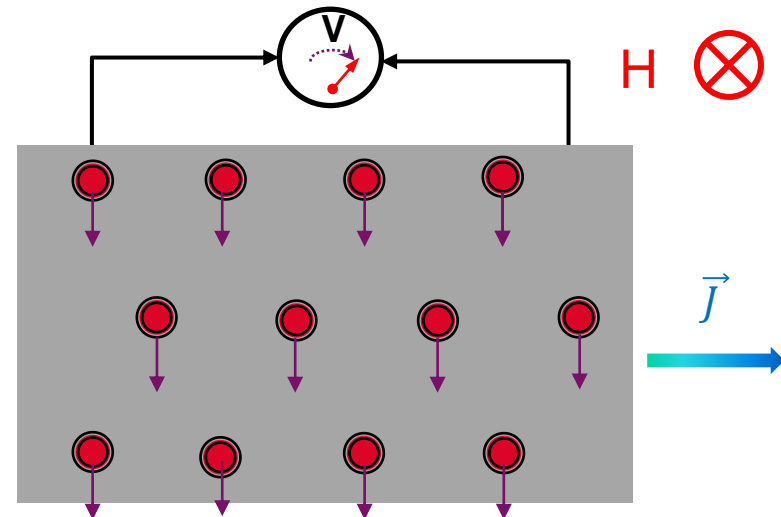
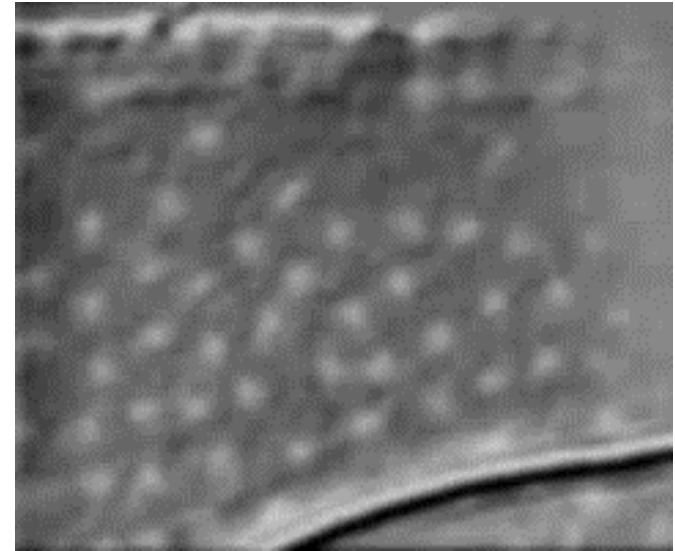


Influence of \vec{j}

- Vx submitted to Lorentz force $\vec{F} = \vec{j} \times \vec{B}$
 - Vx lattice moves at speed v under the action of \vec{j} (collective movement)
 - Generate electrical field $\vec{E} = -v \times \vec{B}$, ($\parallel \vec{j}$)
 - Ohm law : if \exists potential difference, then $\exists R$
 - => non negligible resistivity: flux flow resistivity ρ_{ff}
 - Lattice viscosity : movement limited by / “viscous” force (Magnus force)
 - Origin: normal zone dissipation
 - $\rho_{ff} = \rho_n B / B_{C2}$ ($B/B_{C2} \Rightarrow$ vol. fraction of normal e-)
 - Viscosity $\eta = \phi_0 B / B_{C2}$
 - Constant speed $v = E/B$
 - Elastic energy:
 - Tends to keep Vx equidistant in absence of defects
(*reminder: inter-vortex distance depends on applied field*)
- See also :

<http://www.mn.uio.no/fysikk/english/research/groups/amks/superconductivity/sv/>

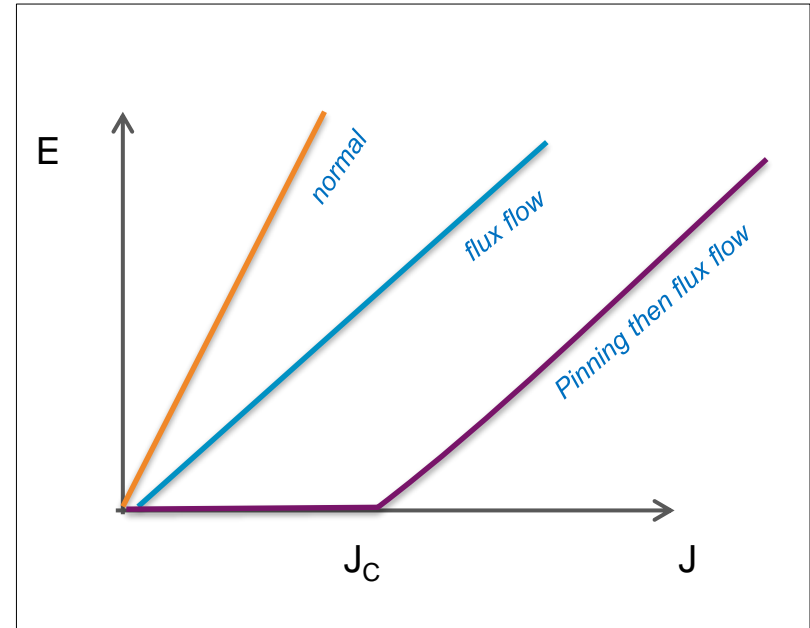
NbSe \rightarrow
25x35 μm



For type II SC



- In practice $R \neq 0$ only for $J > J_C$
- For $J < J_C$
 - $R=0$ (for $J \ll J_C$, close to J_C : some flux creep)
 - V_x are pinned on defects
- J_C : current at which flux flow starts
- No dissipation ? => do pin V_x => do artificially create defects (inclusions, grooves, alloying, damaging ...)
- For $\nearrow J_C$: \nearrow defect density => $\ell \searrow$
 - $\xi \searrow$, $\lambda \nearrow \nearrow$, $\kappa \nearrow \nearrow$ and $H_{C1} \searrow$, $H_{C2} \nearrow$
 - J_C (extrinsic) $\ll J_D$ (intrinsic)
- RF Cavities : **pinning is inefficient**, J_C meaning less: always in the flux flow regime (that is why we want to prevent early V_x penetration and flux trapping during cooldown!)



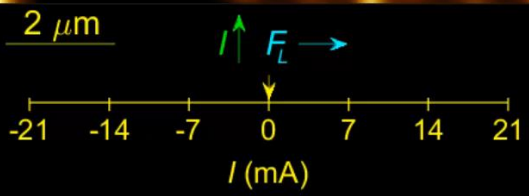
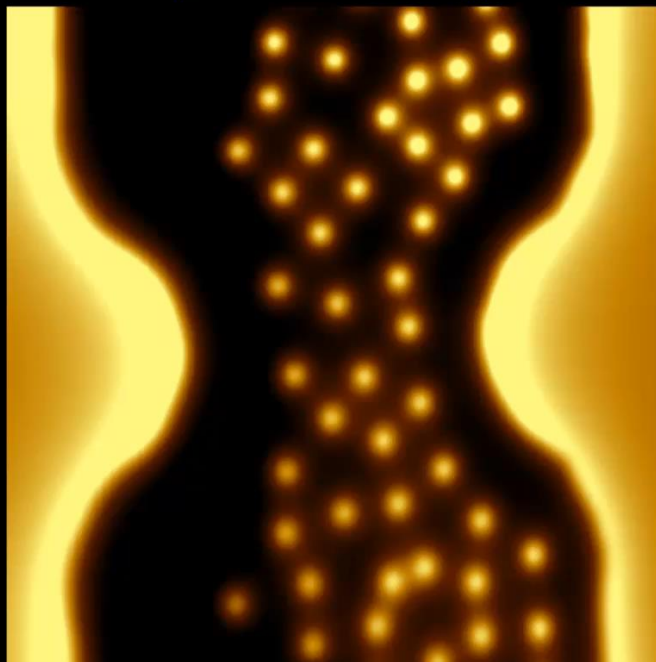
<https://www.eurekalert.org/multimedia/pub/145764.php>

© Dr. Yonathan Anahory

Racah Institute of Physics
The Hebrew University of
Jerusalem

- Lead films
- scanning SQUID-on-tip microscopy technique
- allows magnetic imaging at magnetic sensitivity and high resolution (~50 nm)

Vortex dynamics in Pb film at $B_a = 2.7$ mT



At high currents (high drives) vortices move at 20 km/s and appear as smeared line.

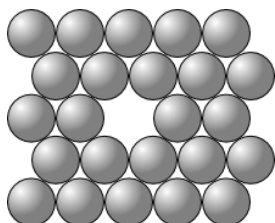
VORTEX (II): PINNING ON CRYSTALLINE DEFECTS

(Introduction)

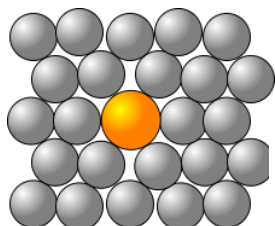


Punctual:

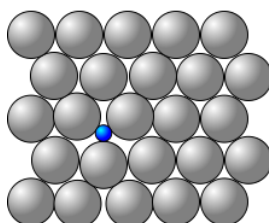
Vacancy



Substitutional atom

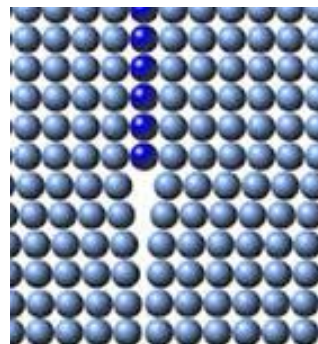


Interstitial atom

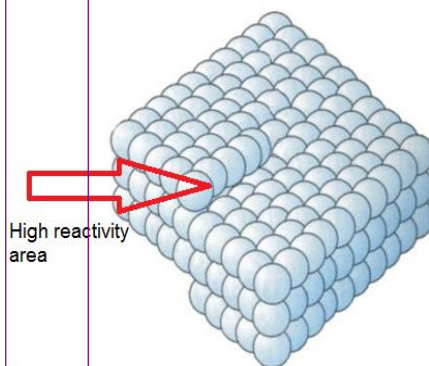


1D:

Edge dislocation

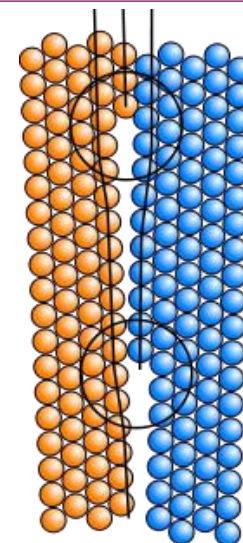
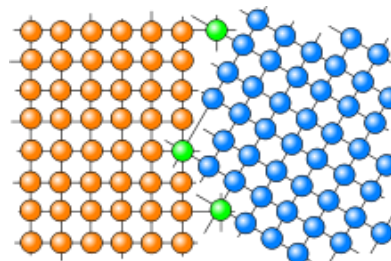


Screw dislocation

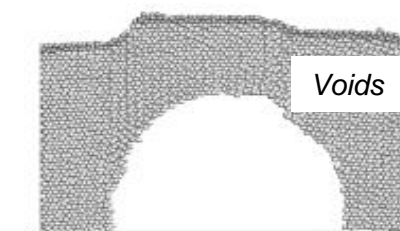
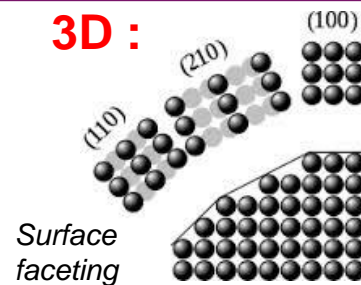


2D :

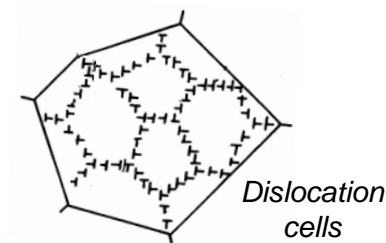
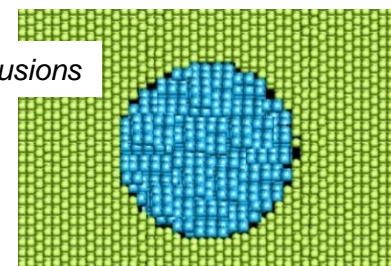
Surfaces, interfaces (GB)



3D :



Inclusions



MORE DETAILS ON PINNING MECHANISMS



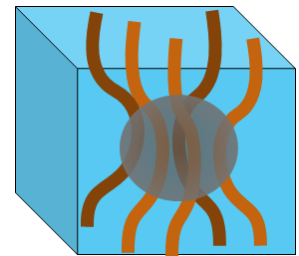
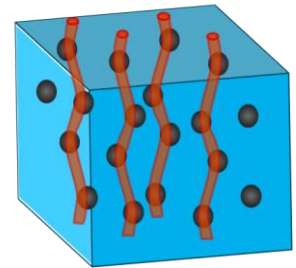
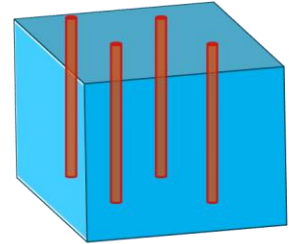
Matsushita : 4 mechanisms from the SC point of view

- **A-** Condensation energy variation (*one saves condensation energy if \exists already a normal zone*)
- **B-** Elastic interactions (*bending of V_x + lattice elastic moduli in SC state < elastic Mod. In normal state, strong interaction with lattice elastic deformation due to crystalline defects-see below*)
- **C-** Magnetic interaction (*if defects $\gg \lambda$, you can treat it like an interface: image vortex + surface barrier => very strong effect*)
- **D-** Kinetic energy interaction (*areas with $\neq \xi$ => \neq in V_x velocities ?*)

IN BRIEF : local effects !!!! (=>2 fluids model not fully OK)

\exists 2 kinds of efficient pinning :

- Strong pinning (surface magnetic pinning) : twinning, voids, non SC aggregates, irradiation defects (columnar), nano-indentations : Dominant mechanism: **A** then **C** then **D**
- Weak pinning centers but many of them: «volume core pinning»
 - Dominant mechanism: **B** ; **B** less efficient than **C** but if they are many pinning centers => results into strong pinning
 - Mechanism **B** efficiency \searrow 3D \rightarrow Interface (G.B) \rightarrow dislocation \rightarrow punctual defects



Pinning Force vs elasticity

■ Efficient pinning:

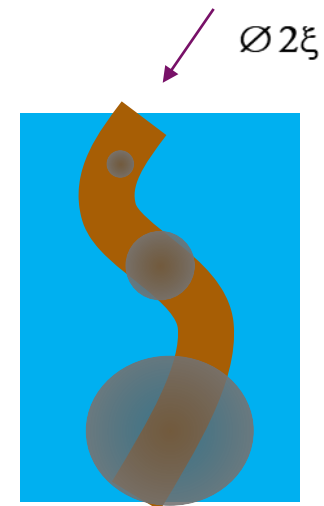
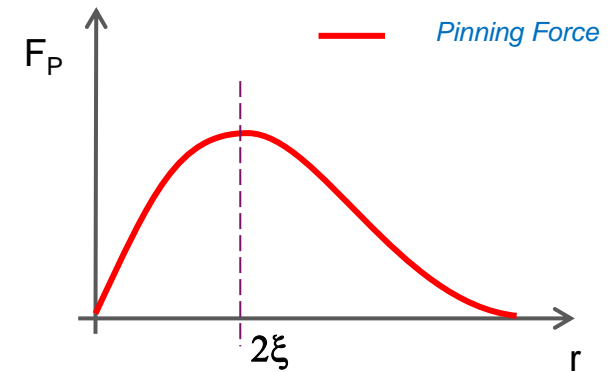
- $F_P(r)$ small for $r \ll 2\xi$ et $r \gg \xi$ *r* - defects \emptyset
- $F_P(r)$, J_C maximum for V_x // defects w. lateral size $\sim 2\xi$ (columnar defects, plane interfaces)
- For inclusions $\emptyset \sim \xi$, interspace d , $J_C \Rightarrow J_C' \sim J_C L/d$ (length fraction L occupied by pinning centers w. d interspace)

- $E_{elastic} \sim \frac{C_{ii}}{2} \int (\nabla \mathbf{u})^2 d^3 \mathbf{r}$ ($\mathbf{u} \sim V_x$ displacement /its ideal position, C_{ij} : elastic constants /length unit)

- Elastic energy influenced by other elastic deformation of the lattice due to the presence of crystalline def

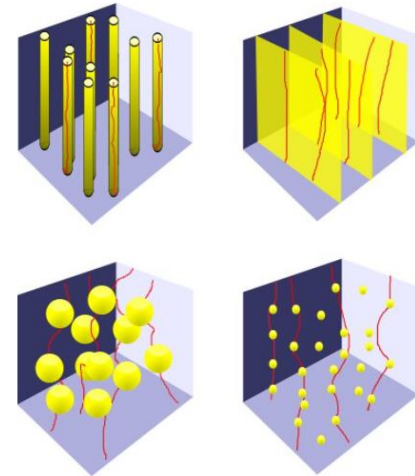
■ Periodicity of the V_x Abrikosov lattice is lost $\Rightarrow V_x$ “polycrystal”, even V_x “glass” or “liquid”...

- \exists complex phase diagrams of V_x states
- Weird dynamic properties (80% of SC literature ...)
- In some SC (HTC): a new material state was discovered: “Bragg glasses”



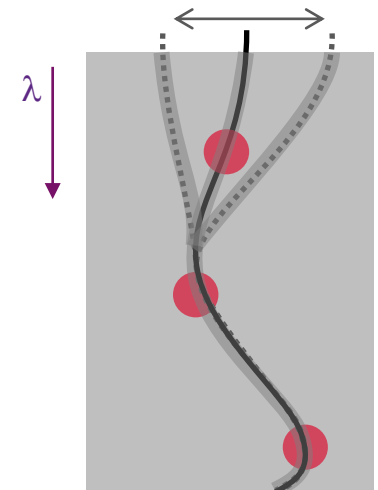
Magnets :

- Pinning efficiency drives J_c (and $R=0$)
- Whenever possible, pinning features are amplified
 - Modification of the mean free path: impurities, deformation, alloying
 - Artificial pinning : voids, inclusions, topological defects



SRF cavities:

- No pinning at high frequency but...
- If they are pinning centers in the material:
 - They can prevent flux lines from being expelled during cooldown (trapped flux lines => oscillating V_x within $\sim \lambda$)
 - => hot spots ! (V_x move in RF field => dissipation)



NEXT:

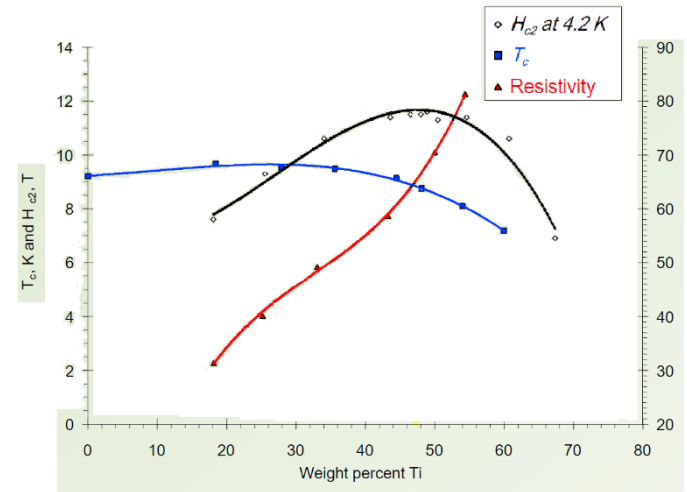
**PART III : OPTIMIZATION OF SC
MATERIAL**

MAGNETS:

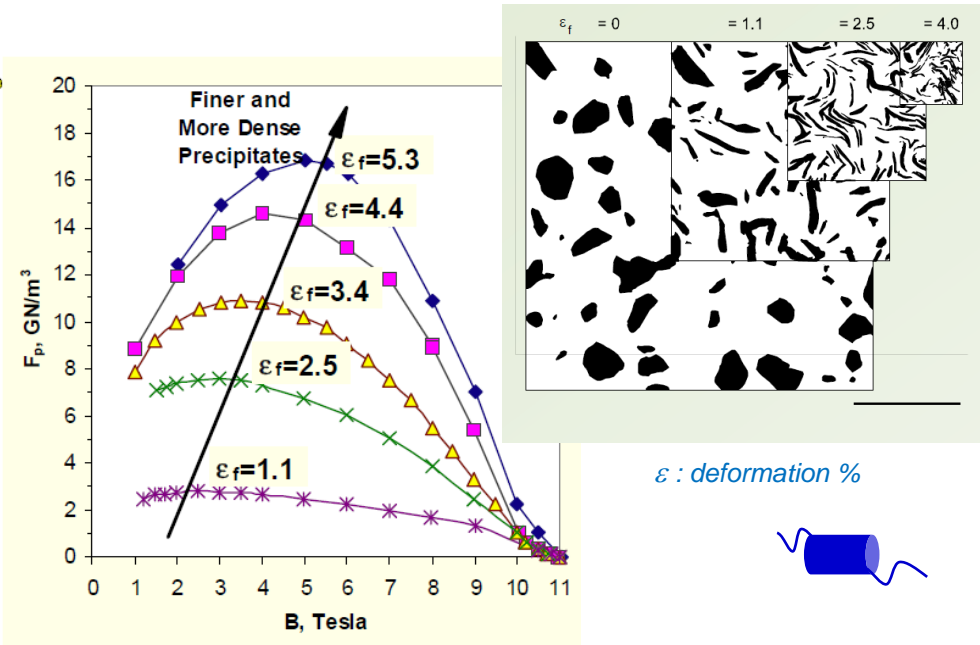
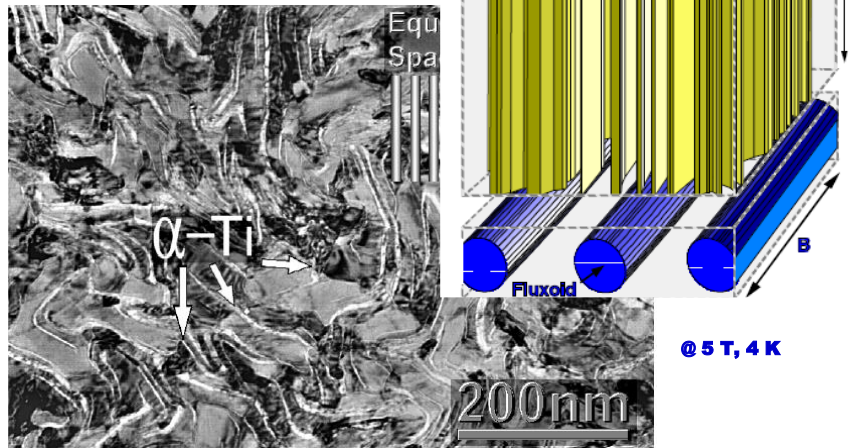
- CONDUCTORS MICROSCOPIC DEVELOPMENTS**
- OTHER ELEMENTS IMPORTANT FOR DESIGN**

J_c Optimization

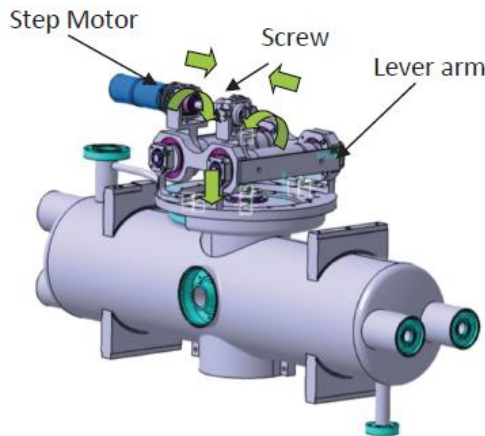
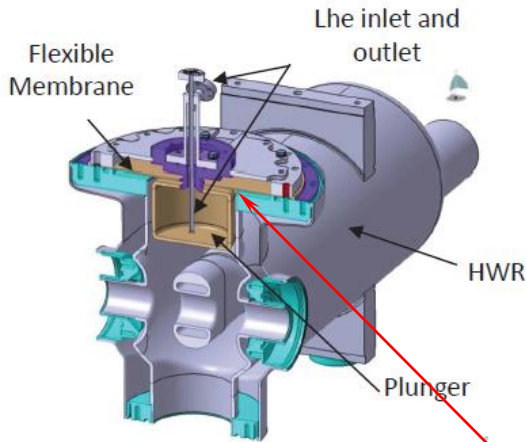
- **Composition:**
 - H_{C2} optimum for 46-48% Ti (but not T_c)
- **Thermal treatments:**
 - => Metallic Ti precipitates (OK in DC, danger in RF)
- **Forming (wiredrawing):**
 - Final microstructure : defects @ the same scale as Vx lattice



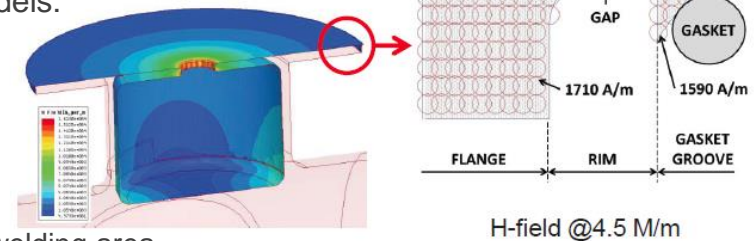
iconographic sources :
Larbaestier CAS 2013
http://fs.magnet.fsu.edu/~lee/asc/pdf_papers/8.pdf
<http://fs.magnet.fsu.edu/~lee/pubs/pjlsctt.pdf>



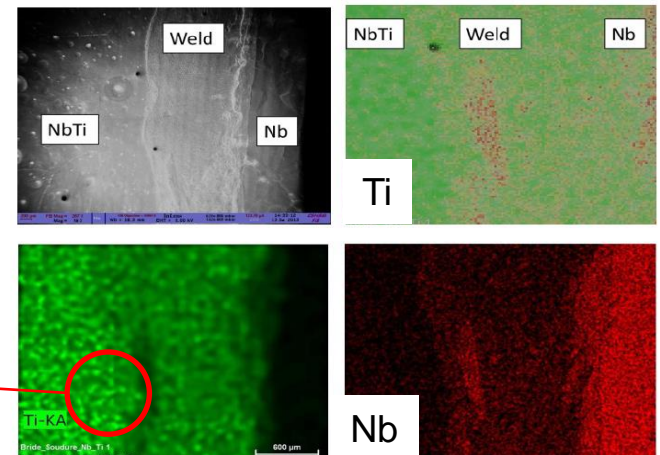
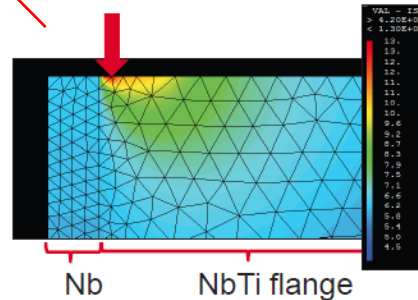
Tuning system : piston/plunger



- To keep the same frequency (as in music)
 - This system is based on the mechanical deformation of a metallic membrane
 - NbTi was chosen for mechanical reasons (more rigid than Nb)
 - Important dissipation occurs a.s.a. $E_{acc} \sim 1\text{MV/m}$ (goal $> 10\text{MV/m}$)
 - Not predicted by thermal models:
 - Field on the gasket ?
 - Checked => no !



- Thermal simulation:
 - Heat comes from the Nb/NbTi welding area



Ti precipitates ($\varnothing \sim 0,4 \mu\text{m}$)
NC Metal => RF dissipation !!!!

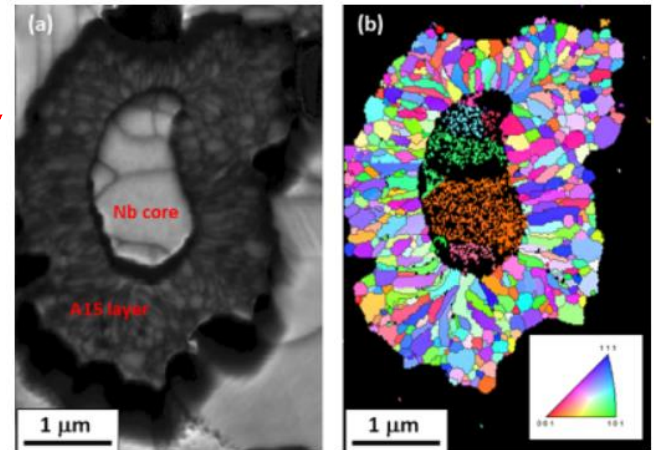
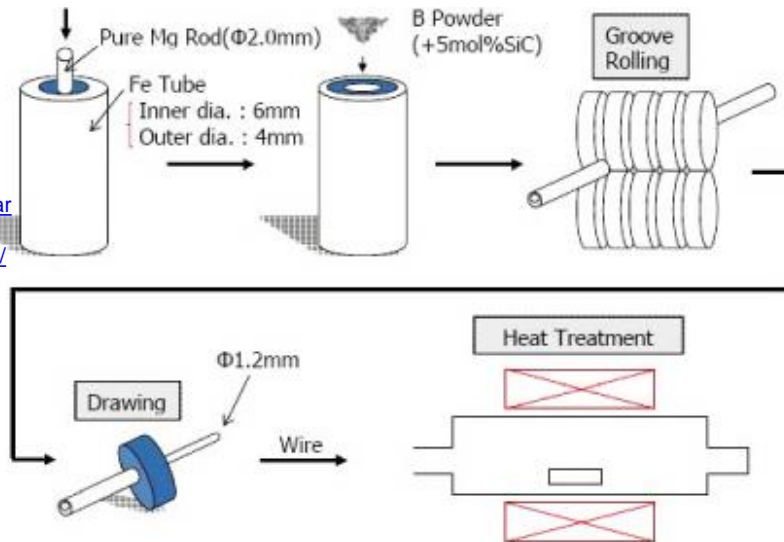
■ Nb₃Sn Fabrication : e.g. “bronze process”

- Nb rod are inserted in a bronze (Cu+Sn) matrix, then co-extrudes
=> thin Nb wire surrounded w. bronze.
- Forming/winding
- High temperature thermal treatment
(problem: solving electrical insulation issues !?)

<http://iopscience.iop.org/article/10.1088/0953-2048/26/5/055008/pdf>

■ MgB₂

<http://iopscience.iop.org/article/10.1088/0953-2048/21/3/032001/fulltext/>



- *Contrary to TiN : here grain boundaries ⊥ J_c*
⇒ *Not the same pinning law !*
- *J_c 1/α ∅ grains*
⇒ *Pinning occurs on grain boundaries !*



Nowadays : wires are commercially produced, then optimization of cables is done within projects (more details in P. Ferracin’s lecture)

■ MonoXtal : Jc maximum for (a,b) planes and minimum when // c axis

■ $\xi_c \ll \xi_a, \xi_b$

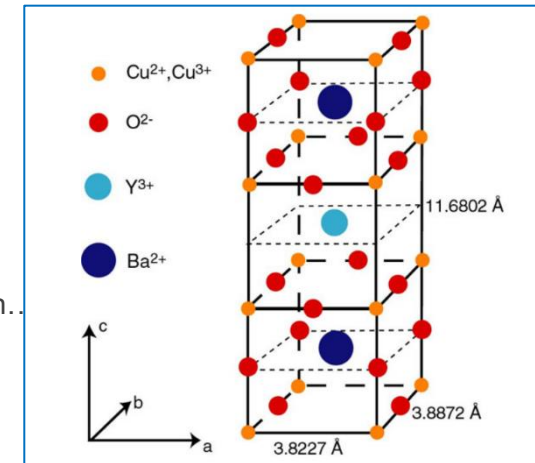
■ Realistic material : polycrystalline, ceramic, fragile...

■ $\xi_c \leq$ disordered area at G.B \Rightarrow grains are decoupled (weak links)

■ Jc when B//(a,b) \gg Jc when B//c

■ \Rightarrow try to introduce preferential orientation (epitaxy)

■ \Rightarrow go to composite material: each layer has a role: epitaxy, mechanical strength...



Main technologies for YBCO coated conductors manufacturing

RABiTS

Ni, Ni-Cr, Ni-V, Ni-W, Ni-Cr-W

IBAD

Substrate 20 x 20 cm
 sputtering Ar⁺ 100 W
 sputtering source Ar⁺ (1.5 kW)
 p = 2 x 10⁻⁴ mbar (Ar + O₂)

ISD

Substrate MgO, YSZ

e-beam evaporator

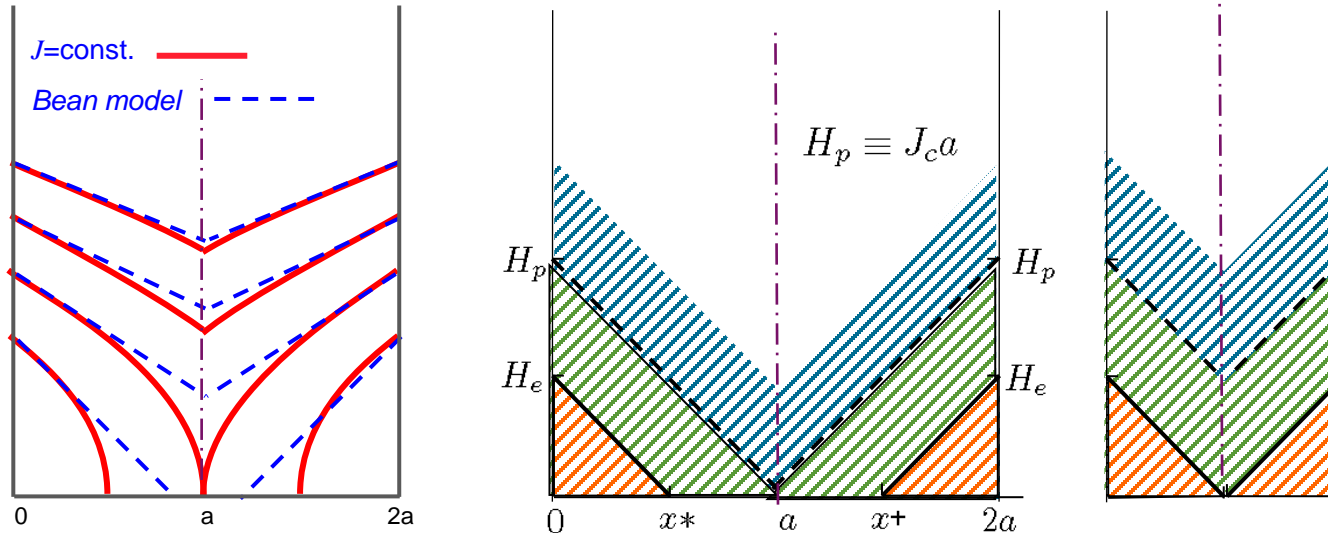
<http://www.c4s.utcluj.ro/Coated%20Conductors.html>

- Current limitation when $B \nearrow$: either intragrain pinning either transition of some G.B. in the normal state (competition between 2 mechanisms)
- IF $B // (ab)$: intrinsic pinning : flux line tend to place themselves in the insulating planes (very efficient mechanism !)

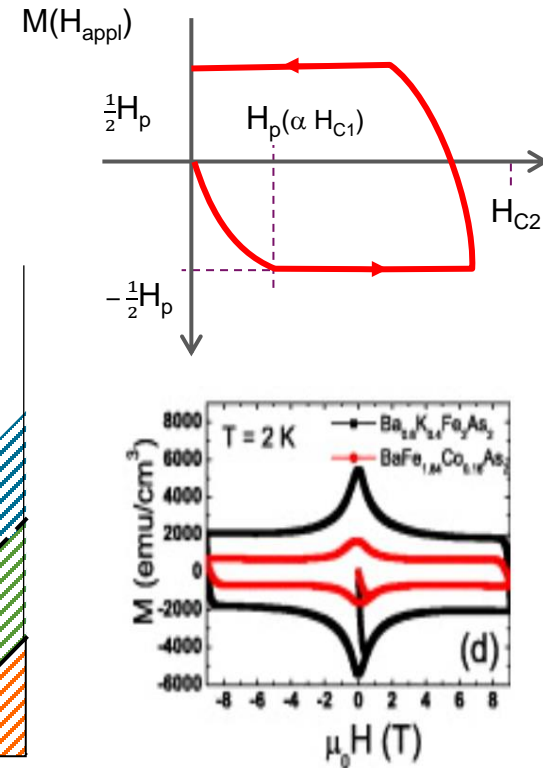
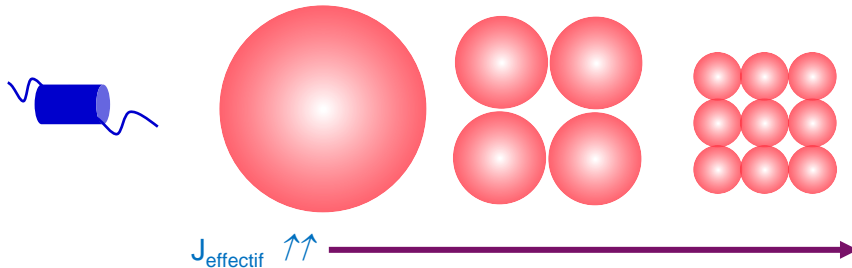
HTC still not much used , but challenges are gigantic (electrical engineering)

Bean model for a thin slab/wire:

- Hyp. : @ $H_{\text{appl}} > H_p$: - $M \sim \text{cst} \sim 1/2 H_p \propto J_c \times a$, can be extended to 3D, e.g. wire
- For a same H_{appl} current density is higher if \varnothing is small



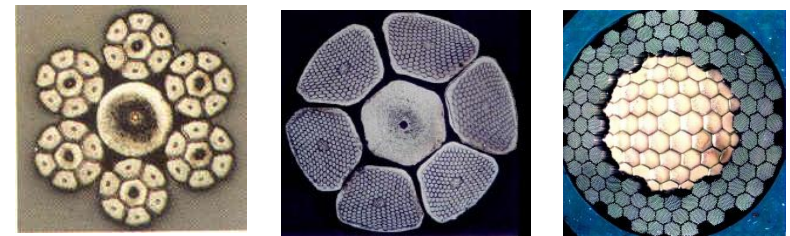
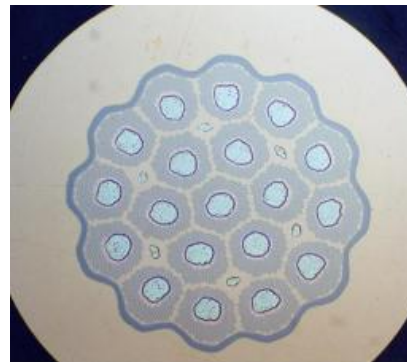
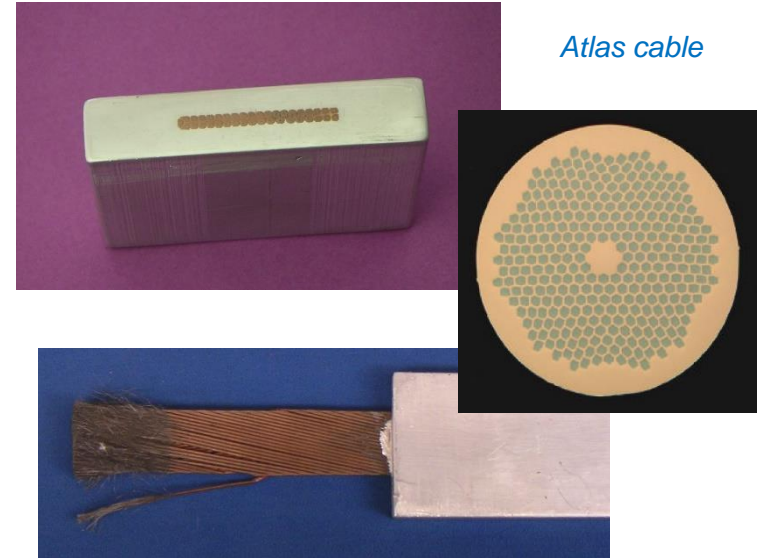
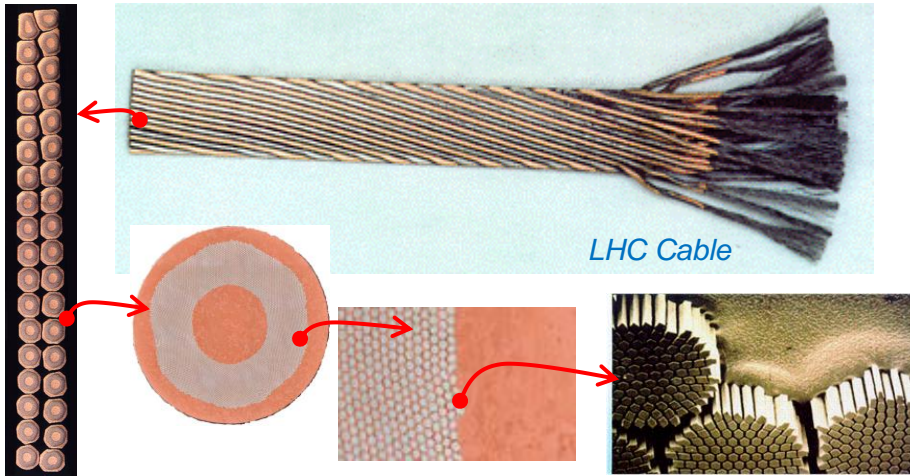
- Consequences on the SC cable design:



Notes

- $J_c \downarrow$ when $H_{\text{appl}} \uparrow$
- Large \varnothing favor instabilities (flux jumps, avalanches instead of progressive penetration)
- Final performance depends on history in field, current, orientation compare to field...

CABLES EXEMPLES



CAVITIES:

- THERMAL / SUPERCONDUCTIVITY COMPROMISE**
- IMPORTANCE OF SURFACE STATE**

-

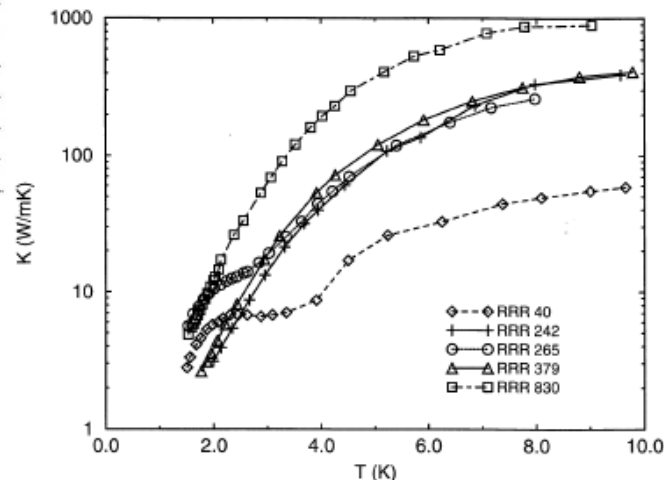
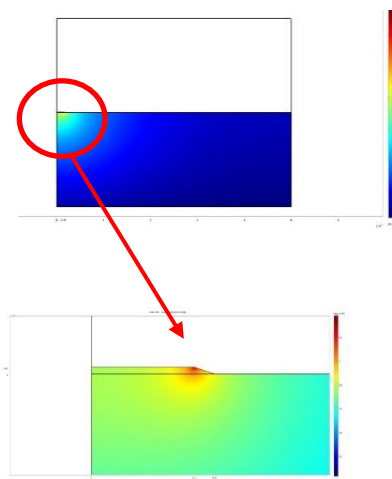
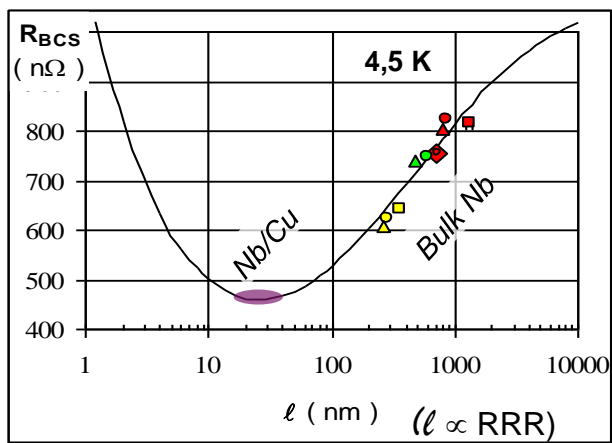
=> High purity (high RRR) well recrystallized bulk Nb, surface polished

■ Surface resistance:

■ Thermal conductivity:

$$R_S = R_{BCS} + R_{Res}$$

$$R_{BCS} = A(\lambda_L^4, \xi_F, \ell, \sqrt{\rho_n}) \frac{\omega^2}{T} e^{-\Delta/KT}$$



RRR: Residual Resistivity Ratio
RRR 30: commercial grade
RRR 300: SRF grade

High RRR not required for superconductivity
But for thermal stabilization of defects

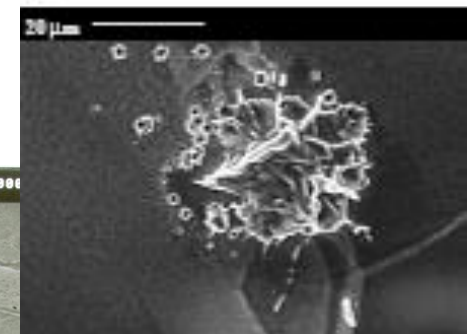
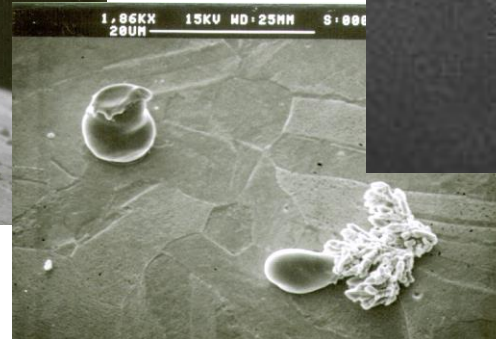
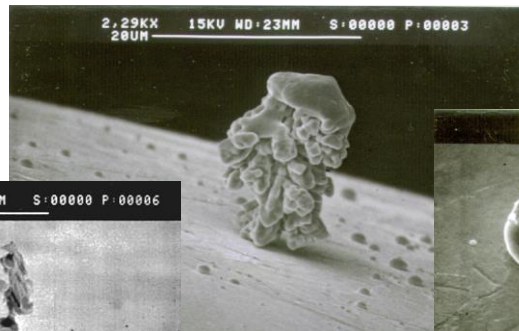
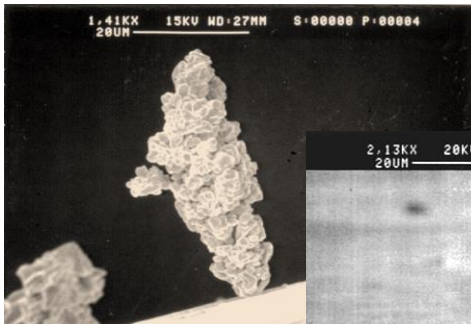
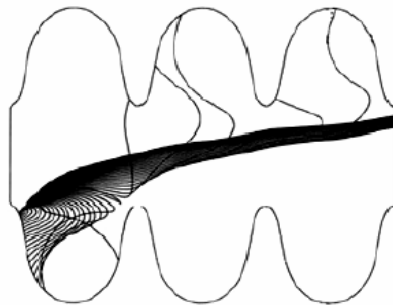
[Koechlin,
Bonin 1996]

NEED FOR QUASI PERFECT MATERIAL ON THE SURFACE !

■ Clean room handling, High Pressure Rinsing (HPR)

- No dust particle, no scratch
- Lowers field emission risk

e⁻ emitted by a field emitting sites disturb the beam



*Dust particles, scratches: "antenna effect", local electric field enhancement
Typically X 50 à 100*

NEED FOR QUASI PERFECT MATERIAL UNDER THE SURFACE !

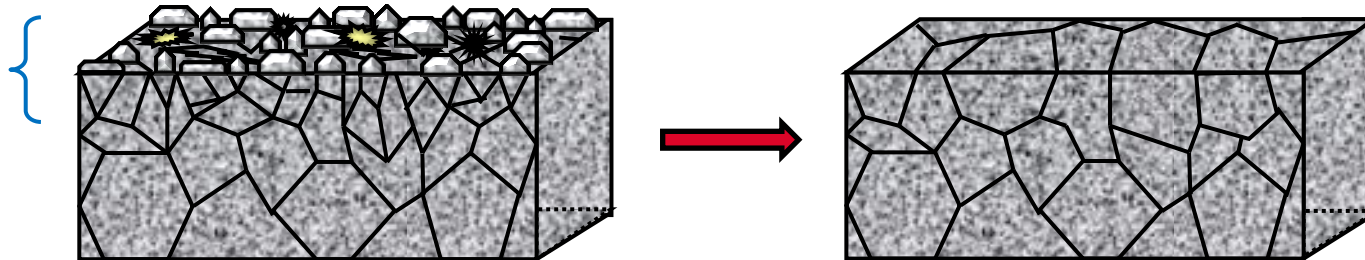


- Morphology => local field enhancement
- Damage => flux pinning, hot spots
- => Surface treatments, annealing ...

} To be avoided in SRF !

Polycrystalline Niobium, smooth and well recrystallized material

Damage layer contamination, roughness



- After fabrication: need to remove 150-200µm on cavity's surface

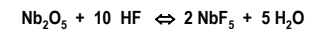
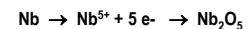
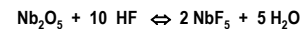
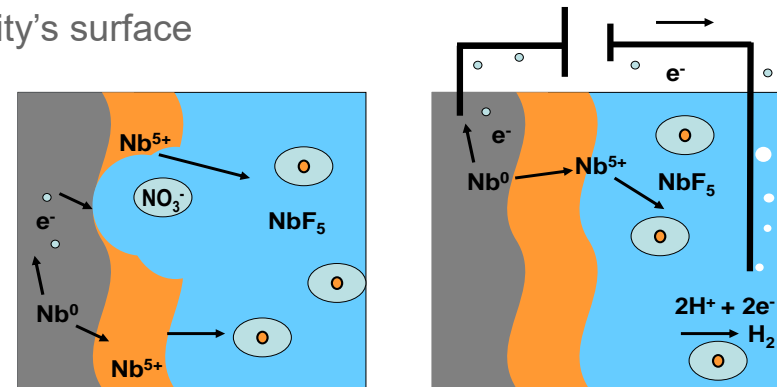
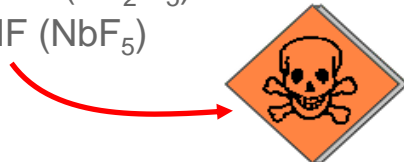
- Chemical polishing (BCP) ~ 1 µm/min
- Electropolishing (EP) ~ 0.3 µm/min

- Basically

- You oxidize Nb⁰ => Nb⁵⁺ (Nb₂O₅)
- You dissolve it with HF (NbF₅)

- EP : ∃ Viscous layer

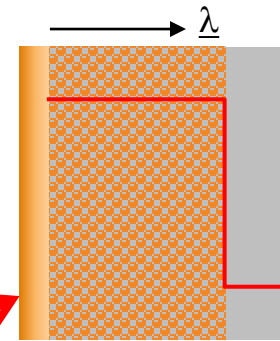
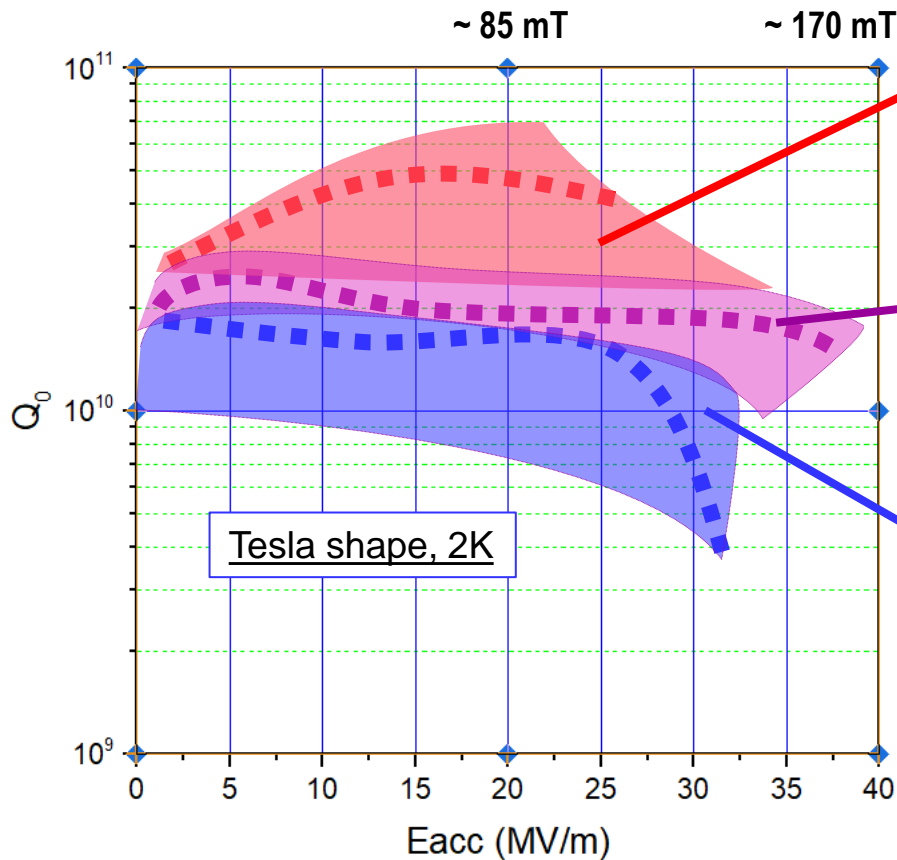
- "Spikes" are etched first
- Smoothing effect : grain edges are less sharp, even if some roughness is retained



Even after best surface treatments they are still a lot of defects at the µm and nm level that have a strong influence on SC properties but are difficult to include in models...

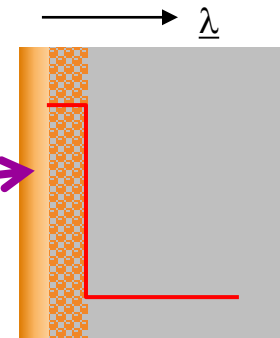
Modification of the surface composition:

- Adjusting superconducting properties
- Preserving bulk high thermal conductivity

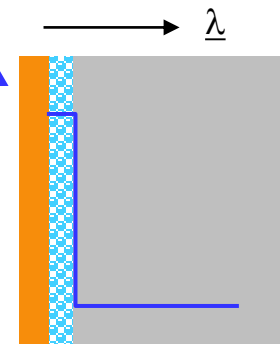


@ 1st order:

- Extra High Q₀: “N-Doping”,
“Medium T baking”
- ⇒ Diffusion of N and/or O >> λ
 - ⇒ Diminution of ℓ , thus Rs, but also T_c and H_{C1}



- Extra High E_{acc}: “N-infusion”,
“Low T baking”
- ⇒ Diffusion of N and/or O << λ
 - ⇒ Prevents Hydride nucleation?



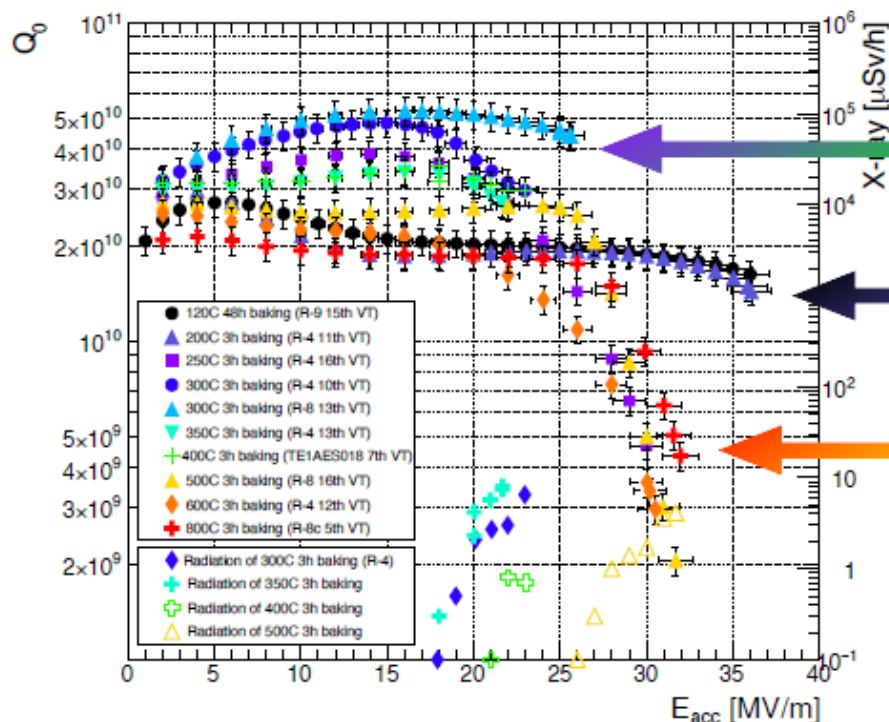
- After polishing
- ⇒ Natural oxide layer (5 nm)
 - ⇒ Impurities (H (main), O, C...) segregation at Metal-oxide interface (see comments for mechanism)

Comparison of Q-E curve



Cavity temperature during measurement

- 120 ~ 600°C baking ... at 2.0 K (2.00~2.01 K)
- 800°C baking ... at 2.1 K (2.07K)



250 ~ 400°C 3 h

- Extremely high Q value and anti-Q slope are observed
- Highest Q value at 2.0 K is ~ 5E10 for 300°C baked cavity
- Magnetic field was trapped before 2 K measurement of 350°C baked cavity → Q value is essentially a bit higher

Standard recipe (120°C 48 h), 200°C 3 h

- 200°C baked cavity follows the standard recipe (120°C 48h)
- Q-E behavior at low E_{acc} is slightly different

500 ~ 800°C 3 h

- High Q value wasn't observed
- HFQS occurred

- Varying the temperature of furnace baking varies Q-E behavior drastically
- In 300 ~ 400°C furnace baking, the cavity is limited at around 25 MV/m?

Nb : $\lambda \sim 50$ nm \Rightarrow only a few 100s nm of SC necessary

(the remaining thickness = mechanical support, thermal transfer)

\Rightarrow Make thin films (1-5 μ m) !

Advantages

- Thermal stability (*substrate cavity = copper, Aluminum, ... W*)
- Cost
- Opens route to innovative materials
- Optimization of R_{BCS} possible (*e.g. by playing with m.f.p*)

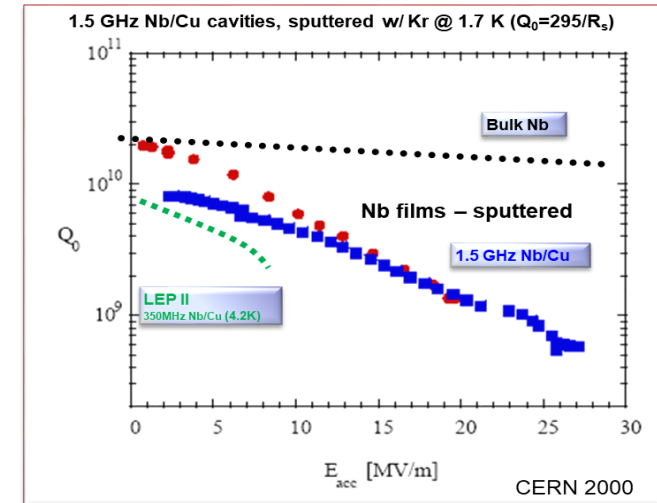
Disadvantages

- Fabrication and surface preparation of substrate (*at least*) as difficult as for bulk Nb
- Steep Q_0 decrease often observed by increase of RF field (*sputtered niobium films*)
- Deposition of innovative materials is very difficult (*large parameters space to be explored*)
- Most of the known SC have been optimized for wire applications (*low HC1, defects, pinning centers...*)
 \Rightarrow most of the literature recipes are not fitted for SRF application ☹ ☹ ☹

Recent breakthrough :

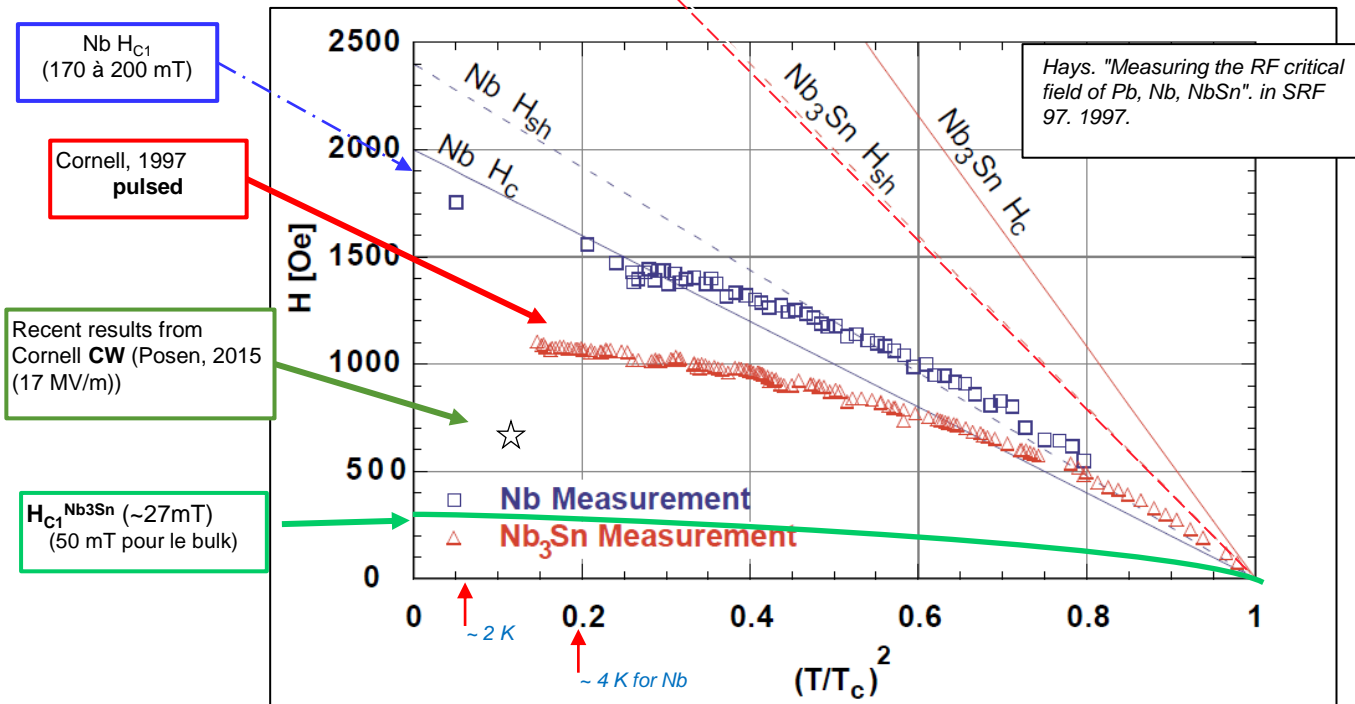
- CERN, Jlab were able to produce Nb film with nearly bulk-like behavior (*50 Y. of R&D!*)^{*}
- Improved substrate preparation + higher energy deposition techniques

** one switches from metallurgy (6000 y. old) to thin film technologies (< 1 century !)*



$H_{SH}^{Nb_3Sn}$
(~ 400 mT @ 0 K)

- Higher Tc materials, e.g. Nb₃Sn: brittle, poor thermal conductivity => go to films (on copper)
- Compounds: less easy to master than pure metals



Nb₃Sn

=> We have to reduce defect density
(yes but which ones?)

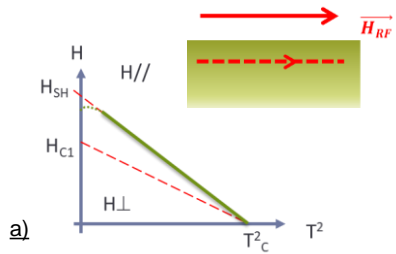
$$H_i = H_i^0 \left[1 - \left(\frac{T}{T_c} \right)^2 \right]$$

- Vortices enter more easily at lower temperature (counter intuitive !)?
 - @ $T \sim T_c$: H is low => low dissipations => easy to thermally stabilize
 - à $T \ll T_c$: H is high => even if small defect => high dissipations => Favors flux jumps

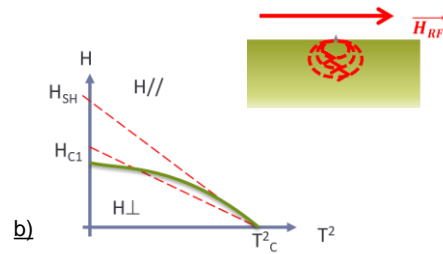
Dissipations :

$$\frac{1}{2} \iint R_s H^2 dS$$

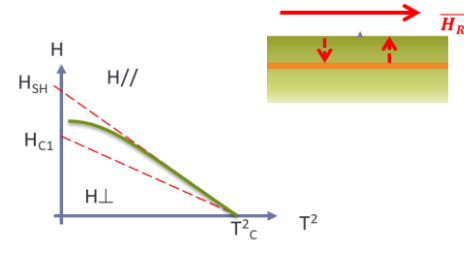
Enhance Q_0 and E_{ACC} altogether



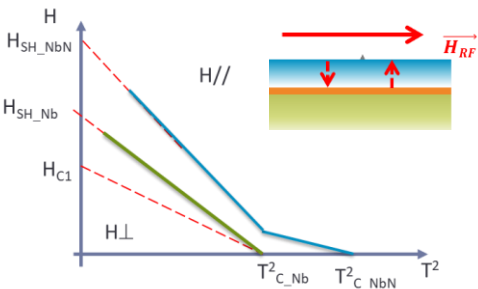
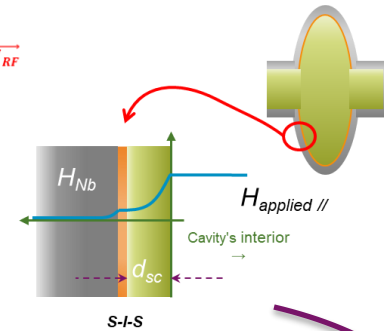
a) Ideal (w/o defect)



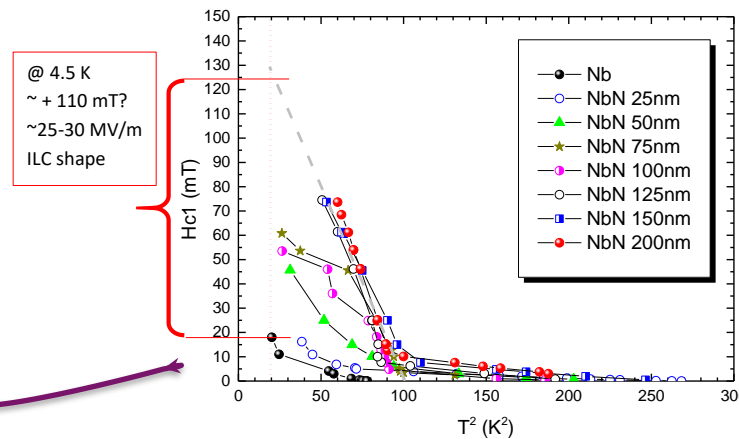
b) Real world
(∃ defects on surface)



Real world
+ dielectric nm layer



Dielectric barrier
+ SC w. higher T_C



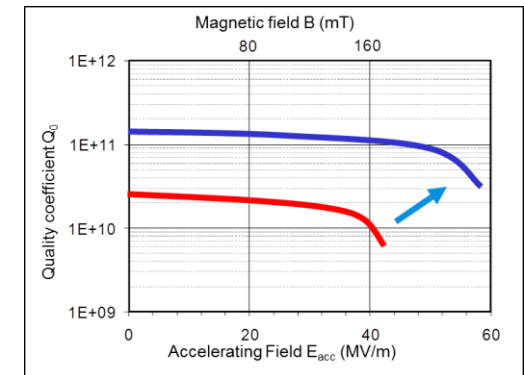
SIS thick Nb/MgO/NbN samples

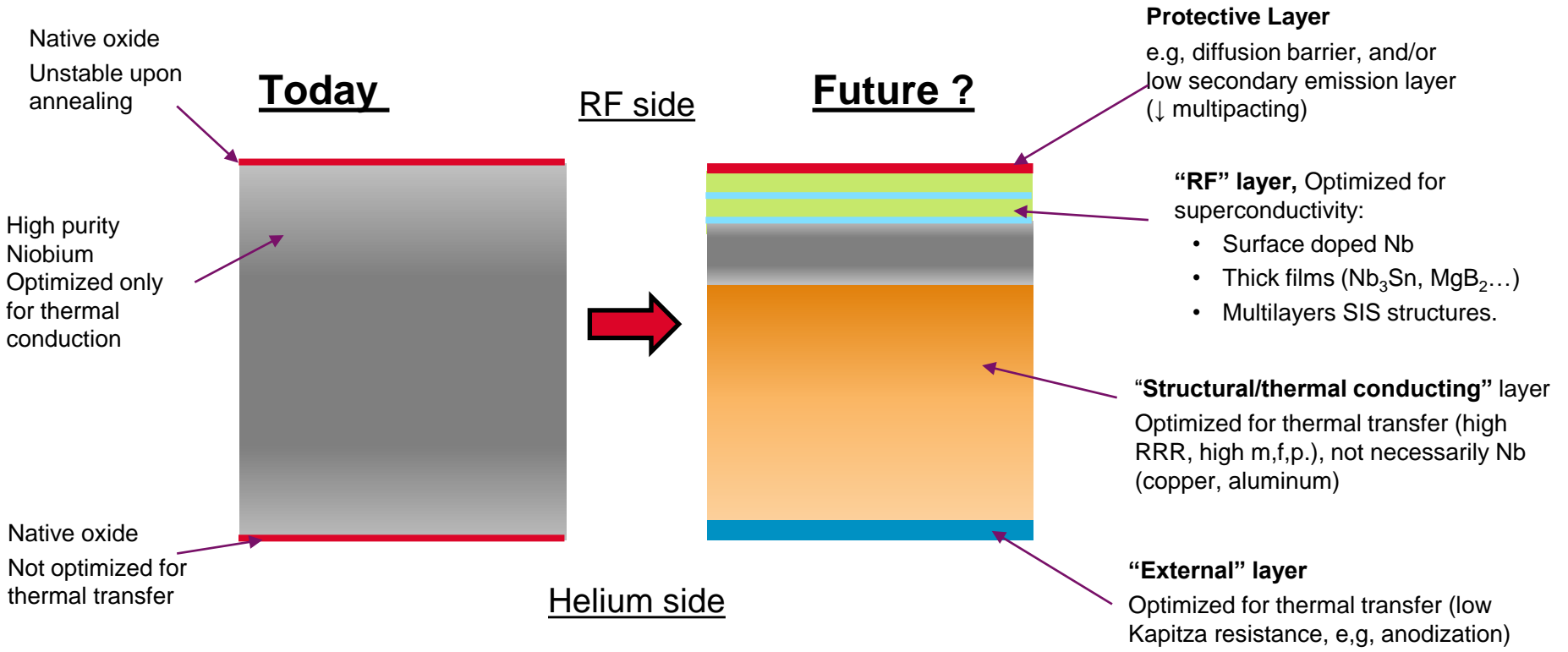
Deposited by MS

Measured by local magnetometry

@ 4.5 K
~ + 110 mT?
~25-30 MV/m
ILC shape

Expected performance
enhancement in cavities





At stakes :
Cooling power (any application!)
Can we go to cryocooling ?

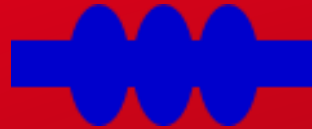
For more details on advanced materials, see
SRF2021 tutorial:
https://indico.frib.msu.edu/event/38/attachments/159/1143/SRF2021_Tutorial_-_Antoine.pdf

CONCLUSION

All advanced technology are limited by material issues

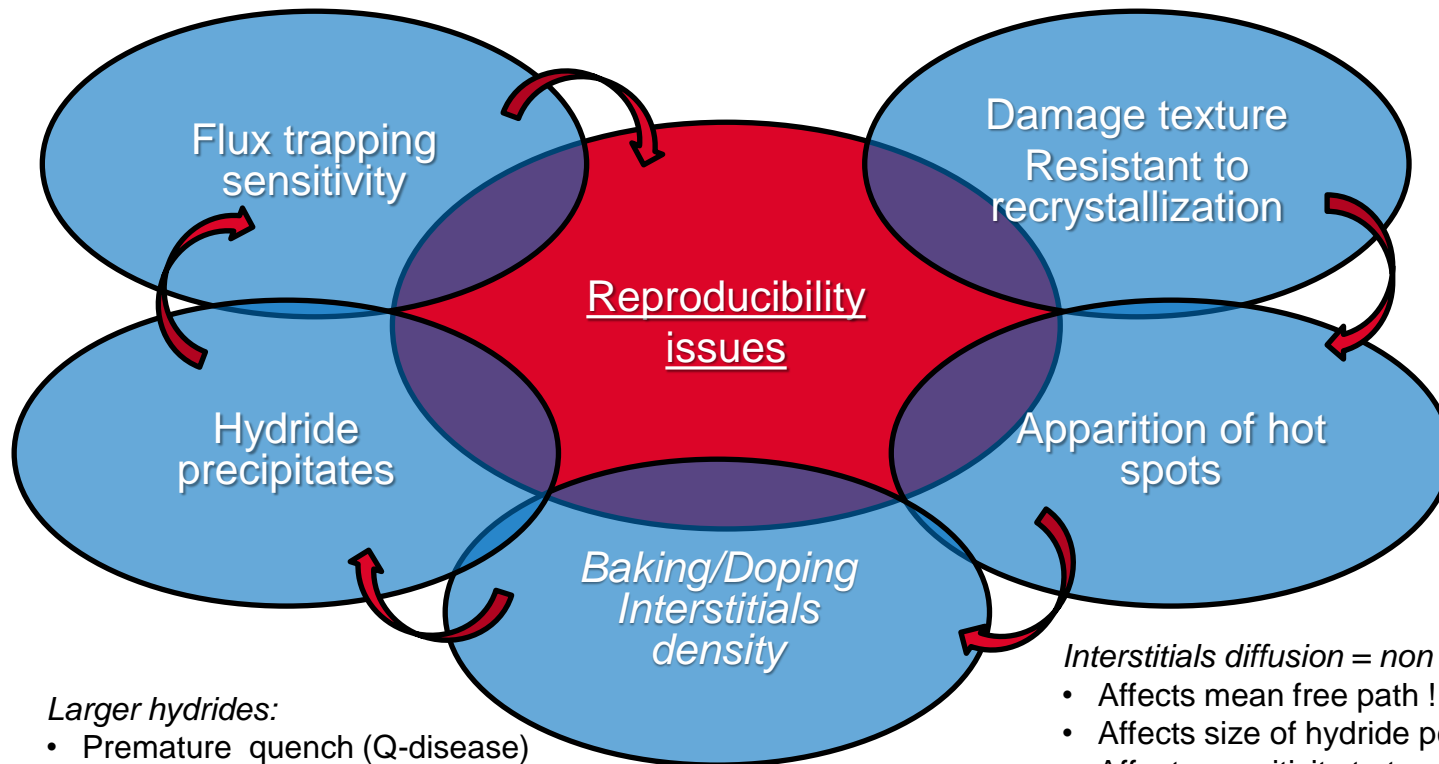
- Once the technology is mastered :
 - Reproducibility issues (lab => large scale production)
 - Production costs
 - Aging problems
 - Not only true for accelerator technology ! (materials for fusion, nuclear power, fuel cells, solar cells , batteries....)
 - Particularly true when a technology is pushed to its ultimate limits (e.g. accelerators)
- Advanced technology project: always a compromise between multiples constraints : mechanical, thermal, stability, superconductivity, costs...
 - Interdisciplinary work mandatory ! (multiple and complementary expertise's are necessary)
 - Do not re-invent the wheel (also meet experts outside the accelerators community !)
 - Be prepared to meet diagnostics issues (Where does the breakdown comes from when many conjugate factors occurs together ? => Diagnostic development)
 - Allow yourself to break traditions (but not too often because it costs money...)

SPARES



Reproducibility

- Main issue on large scale production
- Main issue for lab to lab « recipe » transfer



Hot spots:

- High dislocation density !
- Pinning centers !
- Vortex oscillating in RF ?
- Trapped or premature entrance ?

Larger hydrides:

- Premature quench (Q-disease)
- Strong pinning centers (flux trapping)
- H diffusion slowed by O/N interstitials

Interstitials diffusion = non uniform when dislocations cells

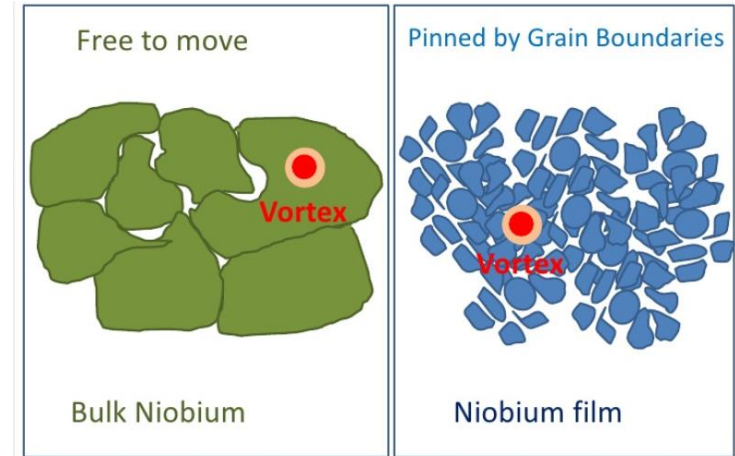
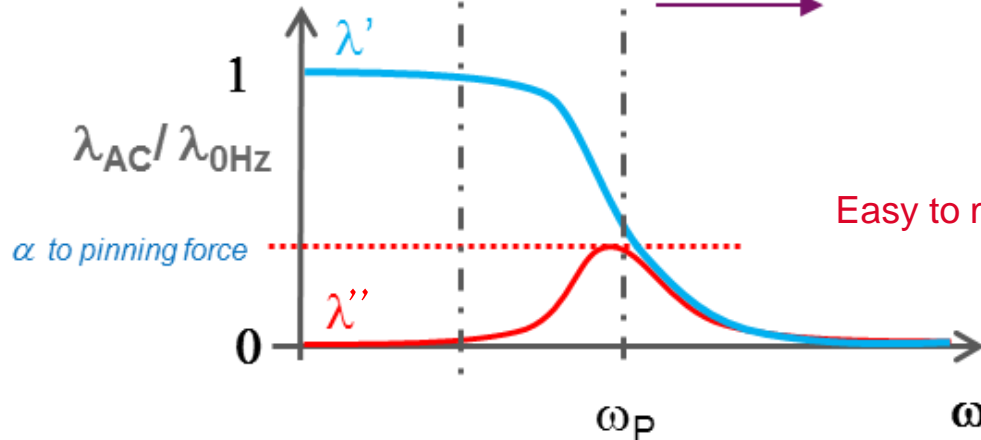
- Affects mean free path !
- Affects size of hydride precipitates !
- Affects sensitivity to trapped flux !
 - Reduce trapped flux due to hydrides
 - Higher sensitivity to trapped flux at high concentration
- **Optimum distribution is yet to be found !**

Depinning frequency

- Theory: see e.g, Palmieri TFSRF 2010
<http://fr.slideshare.net/thinfilmsworkshop/palmieri-rf-losses-trapped-flux>
- Measurement of complex (/effective) penetration depth: $\lambda_{AC} = \lambda' + i\lambda''$
 - Typically used to determine pinning force in SC cables

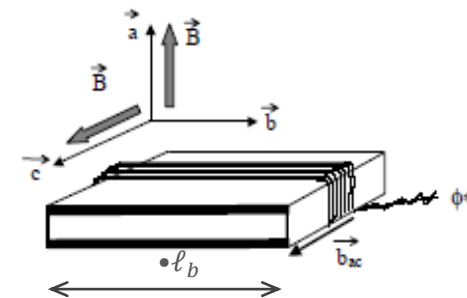
Campbell regime

Pinned vortices, ~ 0 dissipations



Low depinning frequency ω_0

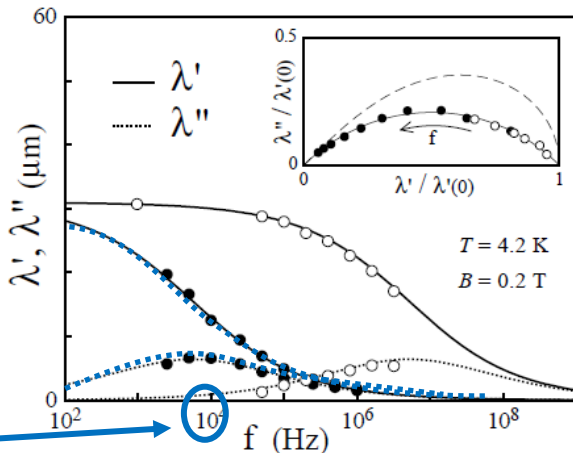
High depinning frequency ω_0



- $\phi_{ac} = \int b_{ac} dS \sim 2\lambda_{ac} l_b b_0$
- At low frequency : $\lambda' \sim \delta_{RF}$ (δ_{RF} = penetration depth in normal state)
- At high frequency $\lambda' \sim \lambda'' \sim \lambda_L \ll \delta_{RF}$

[Electrodynamics of the vortex lattice in untwinned YBaCuO by complex impedance measurements](#) Pautrat 2003

Pinning is very efficient for bulk but not for thin films Nb in the 100 Mhz-1 Ghz range

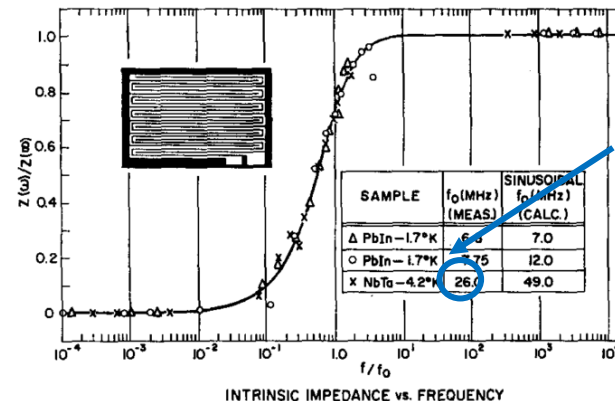


Lütke-Entrup et al
<http://arxiv.org/pdf/cond-mat/9705017.pdf>

$T = 4.2 \text{ K}$
 $B = 0.2 \text{ T}$

Bulk monoX Nb: 10 kHz

FIG. 2. The frequency dependence of the effective penetration depth $\lambda^* = \lambda' + i\lambda''$ in the thick limit ($d \gtrsim 2\delta_f$). Experimental data: (○) $\text{Pb}_{82}\text{In}_{18}$ ($2d = 1.26 \text{ mm}$, $\rho_f = 4.8 \mu\Omega \cdot \text{cm}$, $\Omega_d/2\pi = 6 \text{ MHz}$). (●) pure niobium ($2d = 0.85 \text{ mm}$, $\rho_f = 4.3 \text{ n}\Omega \cdot \text{cm}$, $\Omega_d/2\pi = 6 \text{ kHz}$). Full lines are theoretical



Thin films Nb
Depends on quality,
can reach some 10
GHz; e.g. here 26 GHz,

Gittleman et al

<http://scitation.aip.org/content/aip/journal/jap/39/6/10.1063/1.1656632>

See also

D. Janjušević et al

<http://journals.aps.org/prb/abstract/10.1103/PhysRevB.74.104501>

S. Hall

<http://arxiv.org/abs/1507.04105>

- High depinning frequency: measured on various SC, various film deposition technique, but can vary with quality of the films.
- e.g.: measurements from Gittleman on Nb_3Sn : $\omega_0 \sim 300 \text{ GHz}!!!$
- All thin films show low sensitivity to trapped magnetic flux:

because all the flux is efficiently trapped !!!